

# P-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub>	-100	V		
$R_{DS(on)} V_{GS} = 10 V$	167	mΩ		
$R_{DS(on)}$ $V_{GS} = 4.5 \text{ V}$	178	mΩ		
I <sub>D</sub>	-18	Α		
Configuration	Single			

## **FEATURES**

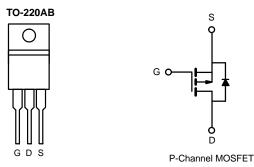




- TrenchFET<sup>®</sup> Power MOSFET
- 100 % R<sub>q</sub> and UIS Tested
- Compliant to RoHS Directive 2002/95/EC

#### **APPLICATIONS**

- Power Switch
- · Load Switch in High Current Applications
- DC/DC Converters



<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)					
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 100	V	
Gate-Source Voltage		V <sub>GS</sub>	± 20	ľ	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 25 °C	I-	- 18	Δ.	
	T <sub>C</sub> = 70 °C	I <sub>D</sub>	- 13		
Pulsed Drain Current (t = 300 μs)		I <sub>DM</sub>	- 100	A	
Avalanche Current		I <sub>AS</sub>	- 10		
Single Avalanche Energy <sup>a</sup>	L = 0.1 mH	E <sub>AS</sub>	31	mJ	
Maximum Power Dissipation <sup>a</sup>	T <sub>C</sub> = 25 °C	В	11.7 <sup>b</sup>	W	
	T <sub>A</sub> = 25 °C <sup>c</sup>	P <sub>D</sub>	1.1		
Operating Junction and Storage Temperature Ra	ange	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Limit	Unit		
Junction-to-Ambient (PCB Mount) <sup>c</sup>	R <sub>thJA</sub>	60	°C/W		
Junction-to-Case (Drain)	R <sub>thJC</sub>	9	- 'C/VV		

#### Notes:

- a. Duty cycle  $\leq$  1 %.
- b. See SOA curve for voltage derating.
- c. When mounted on 1" square PCB (FR-4 material).

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>DS</sub> = 0 V, I <sub>D</sub> = - 250 μA - 100			V		
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 2.5	V	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 250	nA	
		V <sub>DS</sub> = - 60 V, V <sub>GS</sub> = 0 V			- 1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C			- 50	μΑ	
		V <sub>DS</sub> = - 100 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C			- 250	50	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 18			Α	
David Course Co Clata Basistana	P	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 14 A		167			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 12 A		178		mΩ	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 20 V, I <sub>D</sub> = - 14 A		20		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			1460			
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 \text{ V}, V_{DS} = -20 \text{ V}, f = 1 \text{ MHz}$		330		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	]		280			
Total Gate Charge <sup>c</sup>	$Q_g$			67	100		
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = -20 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -14 \text{ A}$		13.5		nC	
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>			14			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.5	2.5	5	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			10	20		
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD}$ = - 20 V, $R_L$ = 2 $\Omega$		11	20		
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$I_D \cong -10 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		42	63	ns	
Fall Time <sup>c</sup>	t <sub>f</sub>	]		12	20		
Drain-Source Body Diode Ratings ar	nd Characteri	stics T <sub>C</sub> = 25 °C <sup>b</sup>					
Continuous Current	I <sub>S</sub>				- 18	^	
Pulsed Current	I <sub>SM</sub>				- 100	Α	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = - 10 A, V <sub>GS</sub> = 0 V		- 0.8	- 1.5	V	
Reverse Recovery Time	t <sub>rr</sub>			38	57	ns	
Peak Reverse Recovery Current	I <sub>RM(REC)</sub>	I <sub>F</sub> = - 10 A, dI/dt = 100 A/μs		2.3	3.5	Α	
Reverse Recovery Charge	Q <sub>rr</sub>	1		40	60	nC	

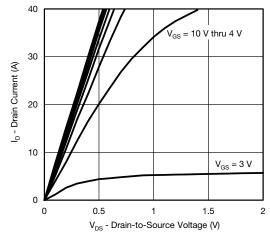
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$  b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

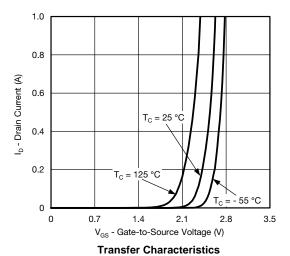
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

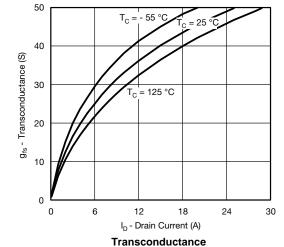


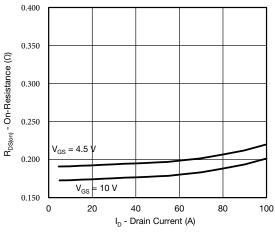
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



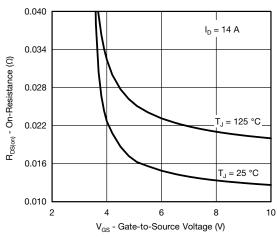




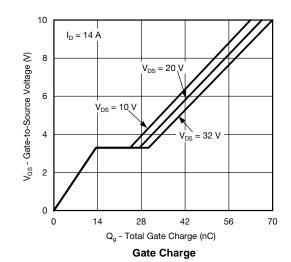




**On-Resistance vs. Drain Current** 

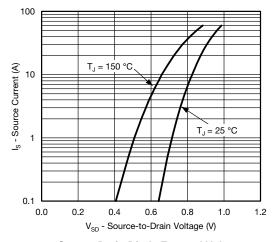


On-Resistance vs. Gate-to-Source Voltage

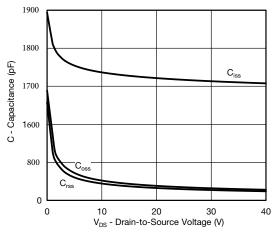




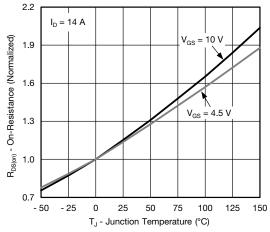
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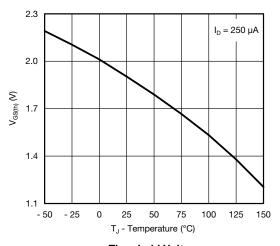
#### Source-Drain Diode Forward Voltage



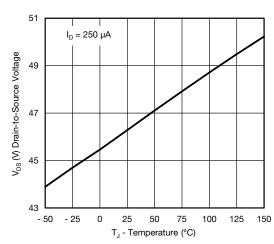
Capacitance



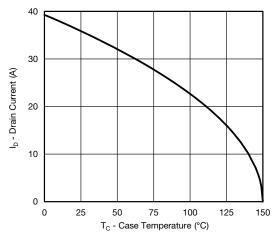
On-Resistance vs. Junction Temperature



**Threshold Voltage** 



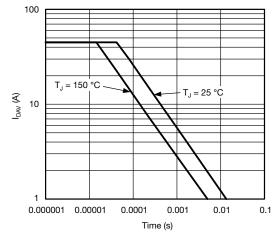
Drain Source Breakdown vs. Junction Temperature

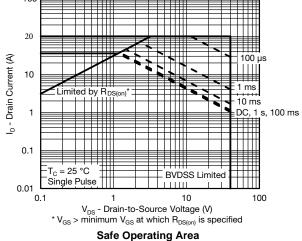


**Current Derating** 

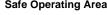


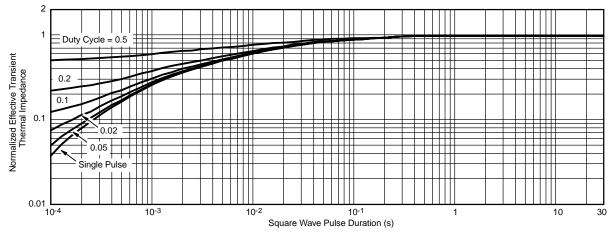
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





Single Pulse Avalanche Current Capability vs. Time





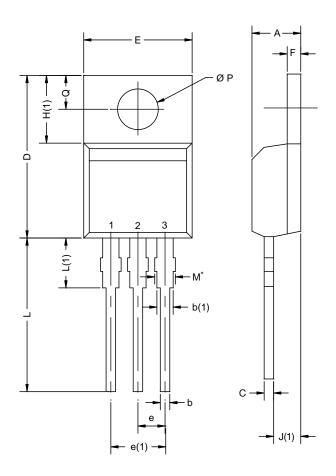
Normalized Thermal Transient Impedance, Junction-to-Case

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## **TO-220AB**



	MILLIN	MILLIMETERS INCHE			
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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